

**Search Notes**

Application/Control No.

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Examiner

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Applicant(s)/Patent under  
Reexamination

STRECK ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	746	8/10/2006	BT
438	747	8/10/2006	BT
438	756	8/10/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	8/10/2006	BT